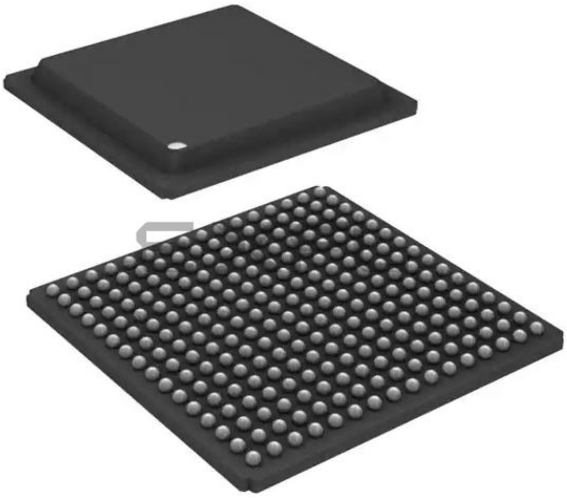
NXP USA Inc. - XPC850SRZT50BU Datasheet



Welcome to E-XFL.COM

Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	50MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	3.3V
Operating Temperature	0°C ~ 95°C (TA)
Security Features	-
Package / Case	256-BGA
Supplier Device Package	256-PBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/xpc850srzt50bu

  - Separate power supply input to operate internal logic at 2.2 V when operating at or below 25 MHz
  - Can be dynamically shifted between high frequency (3.3 V internal) and low frequency (2.2 V internal) operation
- Debug interface
  - Eight comparators: four operate on instruction address, two operate on data address, and two operate on data
  - The MPC850 can compare using the =, ≠, <, and > conditions to generate watchpoints
  - Each watchpoint can generate a breakpoint internally
- 3.3-V operation with 5-V TTL compatibility on all general purpose I/O pins.

3 Electrical and Thermal Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC850. Table 2 provides the maximum ratings.

Table 2. Maximum Ratings

(GND = 0V)

Rating	Symbol	Value	Unit
Supply voltage	VDDH	-0.3 to 4.0	V
	VDDL	-0.3 to 4.0	V
	KAPWR	-0.3 to 4.0	V
	VDDSYN	-0.3 to 4.0	V
Input voltage [1]	V_{in}	GND-0.3 to VDDH + 2.5 V	V
Junction temperature [2]	T_j	0 to 95 (standard) -40 to 95 (extended)	°C
Storage temperature range	T_{stg}	-55 to +150	°C

[1] Functional operating conditions are provided with the DC electrical specifications in Table 5. Absolute maximum ratings are stress ratings only; functional operation at the maxima is not guaranteed. Stress beyond those listed may affect device reliability or cause permanent damage to the device.
CAUTION: All inputs that tolerate 5 V cannot be more than 2.5 V greater than the supply voltage. This restriction applies to power-up and normal operation (that is, if the MPC850 is unpowered, voltage greater than 2.5 V must not be applied to its inputs).

[2] The MPC850, a high-frequency device in a BGA package, does not provide a guaranteed maximum ambient temperature. Only maximum junction temperature is guaranteed. It is the responsibility of the user to consider power dissipation and thermal management. Junction temperature ratings are the same regardless of frequency rating of the device.

This device contains circuitry protecting against damage due to high-static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for example, either GND or V_{CC}). Table 3 provides the package thermal characteristics for the MPC850.

Table 6. Bus Operation Timing [1] (continued)

Num	Characteristic	50 MHz		66 MHz		80 MHz		FFACT	Cap Load (default 50 pF)	Unit
		Min	Max	Min	Max	Min	Max			
B28c	CLKOUT falling edge to WE[0–3] negated GPCM write access TRLX = 0,1 CSNT = 1 write access TRLX = 0, CSNT = 1, EBDF = 1	7.00	14.00	11.00	18.00	9.00	16.00	0.375	50.00	ns
B28d	CLKOUT falling edge to CS negated GPCM write access TRLX = 0,1 CSNT = 1, ACS = 10 or ACS = 11, EBDF = 1	—	14.00	—	18.00	—	16.00	0.375	50.00	ns
B29	WE[0–3] negated to D[0–31], DP[0–3] high-Z GPCM write access, CSNT = 0	3.00	—	6.00	—	4.00	—	0.250	50.00	ns
B29a	WE[0–3] negated to D[0–31], DP[0–3] high-Z GPCM write access, TRLX = 0 CSNT = 1, EBDF = 0	8.00	—	13.00	—	11.00	—	0.500	50.00	ns
B29b	CS negated to D[0–31], DP[0–3], high-Z GPCM write access, ACS = 00, TRLX = 0 & CSNT = 0	3.00	—	6.00	—	4.00	—	0.250	50.00	ns
B29c	CS negated to D[0–31], DP[0–3] high-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10 or ACS = 11, EBDF = 0	8.00	—	13.00	—	11.00	—	0.500	50.00	ns
B29d	WE[0–3] negated to D[0–31], DP[0–3] high-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 0	28.00	—	43.00	—	36.00	—	1.500	50.00	ns
B29e	CS negated to D[0–31], DP[0–3] high-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10 or ACS = 11, EBDF = 0	28.00	—	43.00	—	36.00	—	1.500	50.00	ns
B29f	WE[0–3] negated to D[0–31], DP[0–3] high-Z GPCM write access TRLX = 0, CSNT = 1, EBDF = 1	5.00	—	9.00	—	7.00	—	0.375	50.00	ns
B29g	CS negated to D[0–31], DP[0–3] high-Z GPCM write access TRLX = 0, CSNT = 1, ACS = 10 or ACS = 11, EBDF = 1	5.00	—	9.00	—	7.00	—	0.375	50.00	ns

Figure 4 provides the timing for the synchronous output signals.

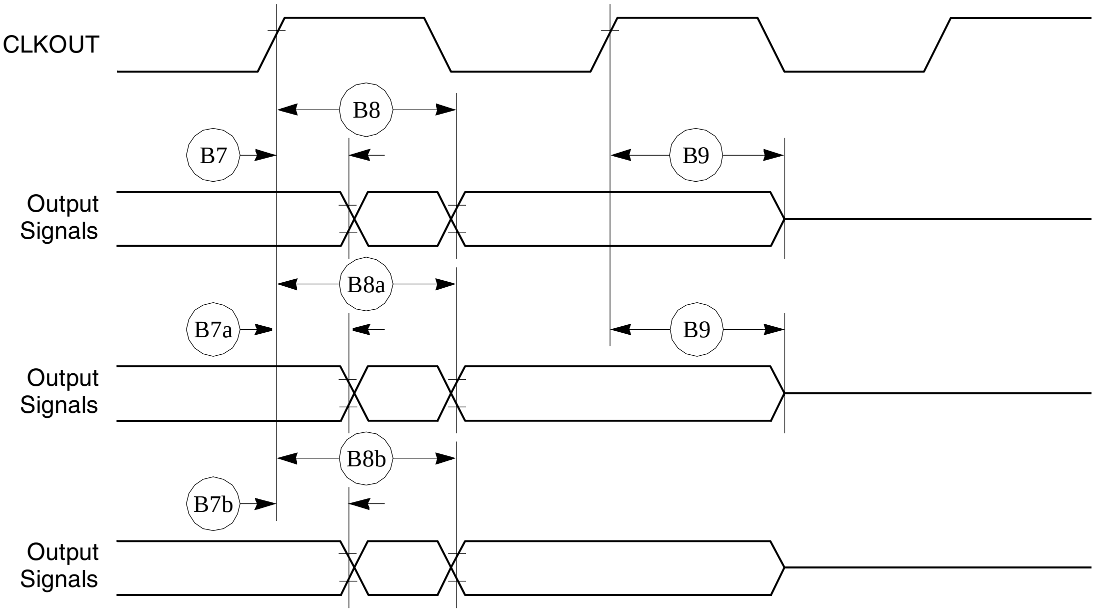


Figure 4. Synchronous Output Signals Timing

Figure 5 provides the timing for the synchronous active pull-up and open-drain output signals.

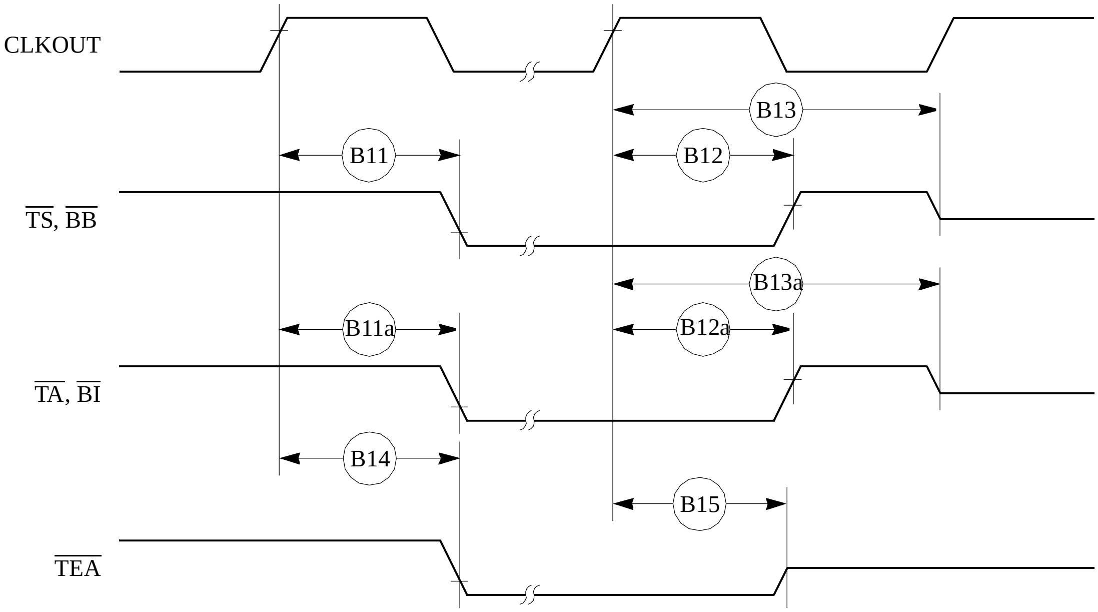


Figure 5. Synchronous Active Pullup and Open-Drain Outputs Signals Timing

Figure 8 provides the timing for the input data controlled by the UPM in the memory controller.

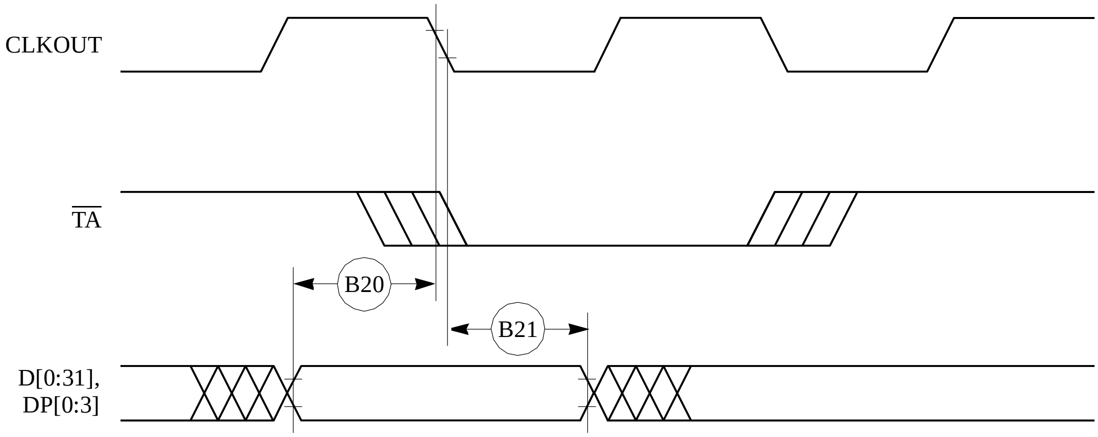


Figure 8. Input Data Timing when Controlled by UPM in the Memory Controller

Figure 9 through Figure 12 provide the timing for the external bus read controlled by various GPCM factors.

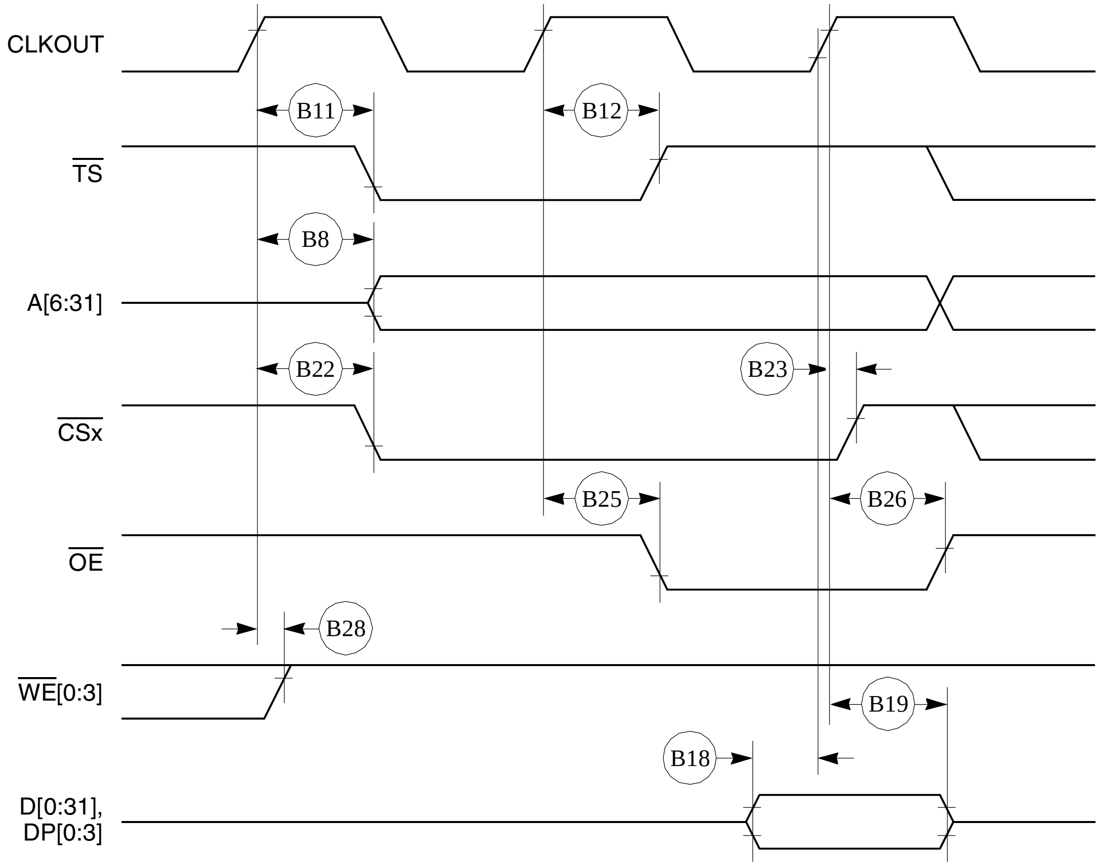


Figure 9. External Bus Read Timing (GPCM Controlled—ACS = 00)

Figure 19 provides the timing for the synchronous external master access controlled by the GPCM.

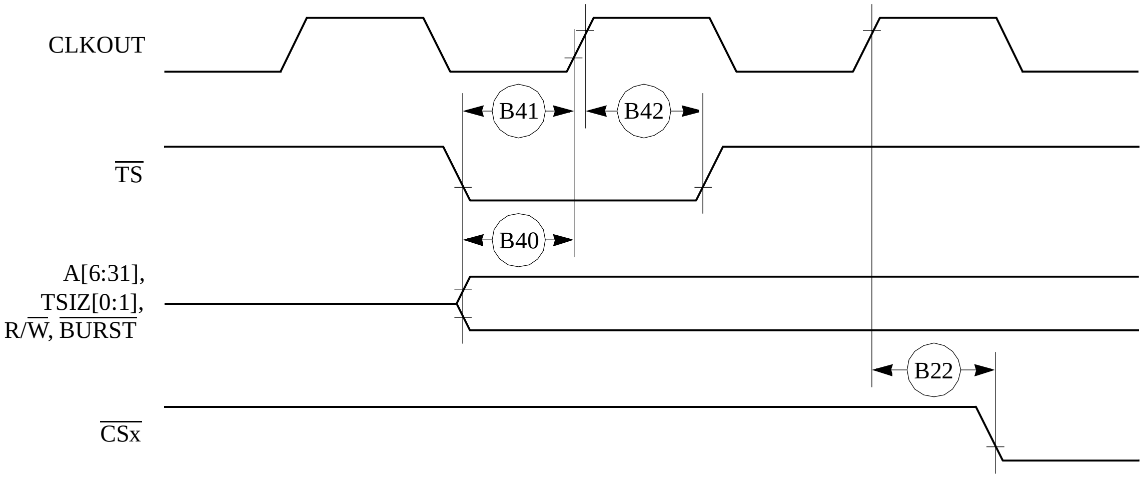


Figure 19. Synchronous External Master Access Timing (GPCM Handled ACS = 00)

Figure 20 provides the timing for the asynchronous external master memory access controlled by the GPCM.

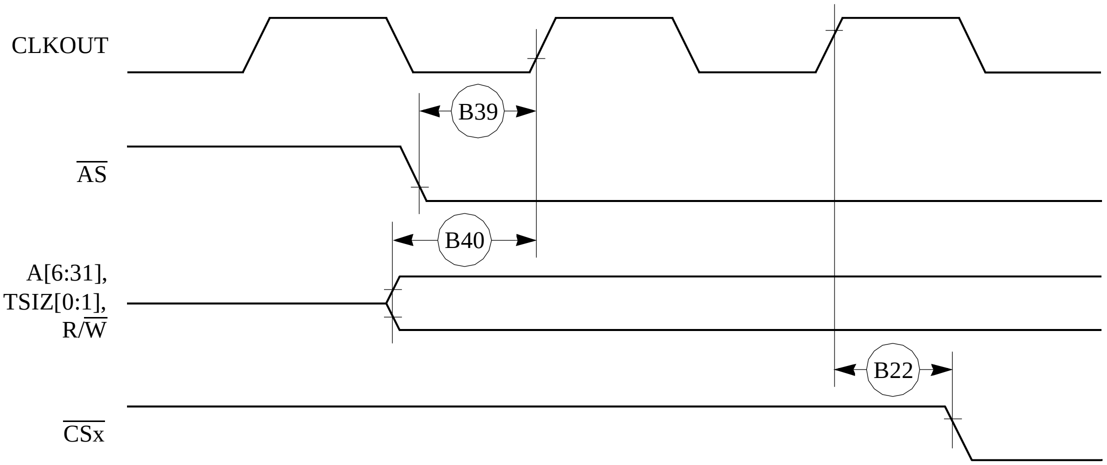


Figure 20. Asynchronous External Master Memory Access Timing (GPCM Controlled—ACS = 00)

Figure 21 provides the timing for the asynchronous external master control signals negation.

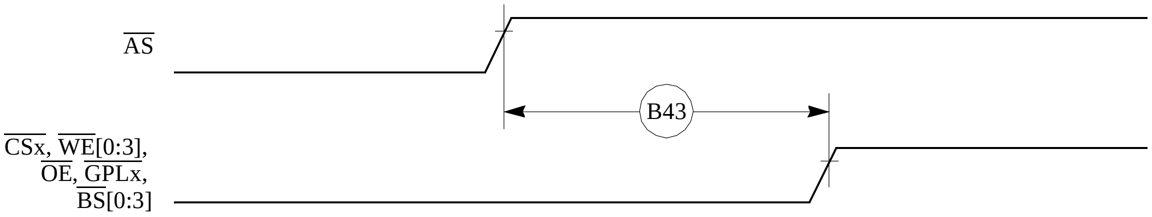


Figure 21. Asynchronous External Master—Control Signals Negation Timing

Table 7 provides interrupt timing for the MPC850.

Table 7. Interrupt Timing

Num	Characteristic[1]	50 MHz		66MHz		80 MHz		Unit
		Min	Max	Min	Max	Min	Max	
I39	$\overline{\text{IRQx}}$ valid to CLKOUT rising edge (set up time)	6.00	—	6.00	—	6.00	—	ns
I40	$\overline{\text{IRQx}}$ hold time after CLKOUT.	2.00	—	2.00	—	2.00	—	ns
I41	$\overline{\text{IRQx}}$ pulse width low	3.00	—	3.00	—	3.00	—	ns
I42	$\overline{\text{IRQx}}$ pulse width high	3.00	—	3.00	—	3.00	—	ns
I43	$\overline{\text{IRQx}}$ edge-to-edge time	80.00	—	121.0	—	100.0	—	ns

[1] The timings I39 and I40 describe the testing conditions under which the $\overline{\text{IRQ}}$ lines are tested when being defined as level sensitive. The $\overline{\text{IRQ}}$ lines are synchronized internally and do not have to be asserted or negated with reference to the CLKOUT.

The timings I41, I42, and I43 are specified to allow the correct function of the $\overline{\text{IRQ}}$ lines detection circuitry, and has no direct relation with the total system interrupt latency that the MPC850 is able to support

Figure 22 provides the interrupt detection timing for the external level-sensitive lines.

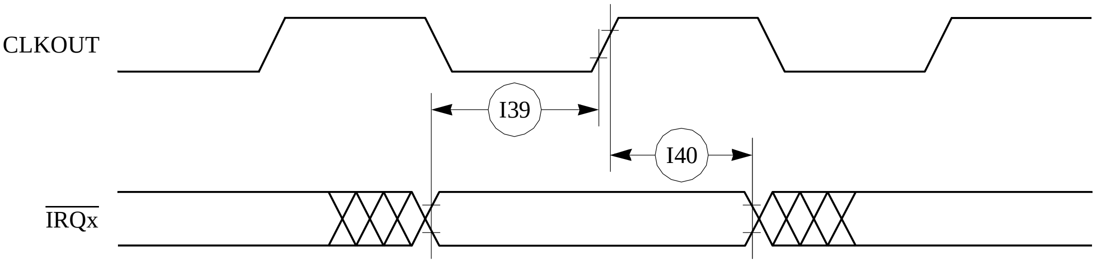


Figure 22. Interrupt Detection Timing for External Level Sensitive Lines

Figure 23 provides the interrupt detection timing for the external edge-sensitive lines.

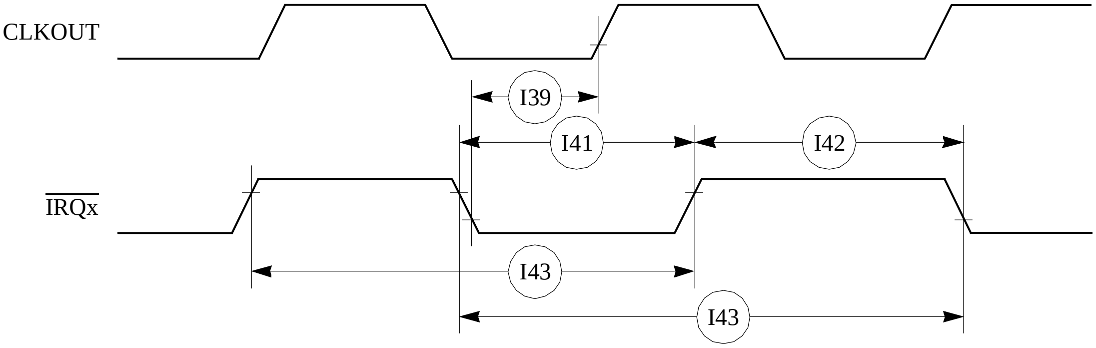


Figure 23. Interrupt Detection Timing for External Edge Sensitive Lines

Table 8 shows the PCMCIA timing for the MPC850.

Table 8. PCMCIA Timing

Num	Characteristic	50MHz		66MHz		80 MHz		FFACTOR	Unit
		Min	Max	Min	Max	Min	Max		
P44	A[6–31], $\overline{\text{REG}}$ valid to PCMCIA strobe asserted. [1]	13.00	—	21.00	—	17.00	—	0.750	ns
P45	A[6–31], $\overline{\text{REG}}$ valid to ALE negation.[1]	18.00	—	28.00	—	23.00	—	1.000	ns
P46	CLKOUT to $\overline{\text{REG}}$ valid	5.00	13.00	8.00	16.00	6.00	14.00	0.250	ns
P47	CLKOUT to $\overline{\text{REG}}$ Invalid.	6.00	—	9.00	—	7.00	—	0.250	ns
P48	CLKOUT to $\overline{\text{CE1}}$, $\overline{\text{CE2}}$ asserted.	5.00	13.00	8.00	16.00	6.00	14.00	0.250	
P49	CLKOUT to $\overline{\text{CE1}}$, $\overline{\text{CE2}}$ negated.	5.00	13.00	8.00	16.00	6.00	14.00	0.250	ns
P50	CLKOUT to $\overline{\text{PCOE}}$, $\overline{\text{IORD}}$, $\overline{\text{PCWE}}$, $\overline{\text{IOWR}}$ assert time.	—	11.00	—	11.00	—	11.00	—	ns
P51	CLKOUT to $\overline{\text{PCOE}}$, $\overline{\text{IORD}}$, $\overline{\text{PCWE}}$, $\overline{\text{IOWR}}$ negate time.	2.00	11.00	2.00	11.00	2.00	11.00	—	ns
P52	CLKOUT to ALE assert time	5.00	13.00	8.00	16.00	6.00	14.00	0.250	ns
P53	CLKOUT to ALE negate time	—	13.00	—	16.00	—	14.00	0.250	ns
P54	$\overline{\text{PCWE}}$, $\overline{\text{IOWR}}$ negated to D[0–31] invalid.[1]	3.00	—	6.00	—	4.00	—	0.250	ns
P55	$\overline{\text{WAIT\_B}}$ valid to CLKOUT rising edge.[1]	8.00	—	8.00	—	8.00	—	—	ns
P56	CLKOUT rising edge to $\overline{\text{WAIT\_B}}$ invalid.[1]	2.00	—	2.00	—	2.00	—	—	ns

[1] PSST = 1. Otherwise add PSST times cycle time.
PSHT = 0. Otherwise add PSHT times cycle time.

These synchronous timings define when the $\overline{\text{WAIT\_B}}$ signal is detected in order to freeze (or relieve) the PCMCIA current cycle. The $\overline{\text{WAIT\_B}}$ assertion will be effective only if it is detected 2 cycles before the PSL timer expiration. See PCMCIA Interface in the MPC850 PowerQUICC User's Manual.

Table 11 shows the reset timing for the MPC850.

Table 11. Reset Timing

Num	Characteristic	50 MHz		66MHz		80 MHz		FFACTOR	Unit
		Min	Max	Min	Max	Min	Max		
R69	CLKOUT to $\overline{\text{HRESET}}$ high impedance	—	20.00	—	20.00	—	20.00	—	ns
R70	CLKOUT to $\overline{\text{SRESET}}$ high impedance	—	20.00	—	20.00	—	20.00	—	ns
R71	$\overline{\text{RSTCONF}}$ pulse width	340.00	—	515.00	—	425.00	—	17.000	ns
R72		—	—	—	—	—	—	—	
R73	Configuration data to $\overline{\text{HRESET}}$ rising edge set up time	350.00	—	505.00	—	425.00	—	15.000	ns
R74	Configuration data to $\overline{\text{RSTCONF}}$ rising edge set up time	350.00	—	350.00	—	350.00	—	—	ns
R75	Configuration data hold time after $\overline{\text{RSTCONF}}$ negation	0.00	—	0.00	—	0.00	—	—	ns
R76	Configuration data hold time after $\overline{\text{HRESET}}$ negation	0.00	—	0.00	—	0.00	—	—	ns
R77	$\overline{\text{HRESET}}$ and $\overline{\text{RSTCONF}}$ asserted to data out drive	—	25.00	—	25.00	—	25.00	—	ns
R78	$\overline{\text{RSTCONF}}$ negated to data out high impedance.	—	25.00	—	25.00	—	25.00	—	ns
R79	CLKOUT of last rising edge before chip tristates $\overline{\text{HRESET}}$ to data out high impedance.	—	25.00	—	25.00	—	25.00	—	ns
R80	DSDI, DSCK set up	60.00	—	90.00	—	75.00	—	3.000	ns
R81	DSDI, DSCK hold time	0.00	—	0.00	—	0.00	—	—	ns
R82	$\overline{\text{SRESET}}$ negated to CLKOUT rising edge for DSDI and DSCK sample	160.00	—	242.00	—	200.00	—	8.000	ns

Figure 31 shows the reset timing for the data bus configuration.

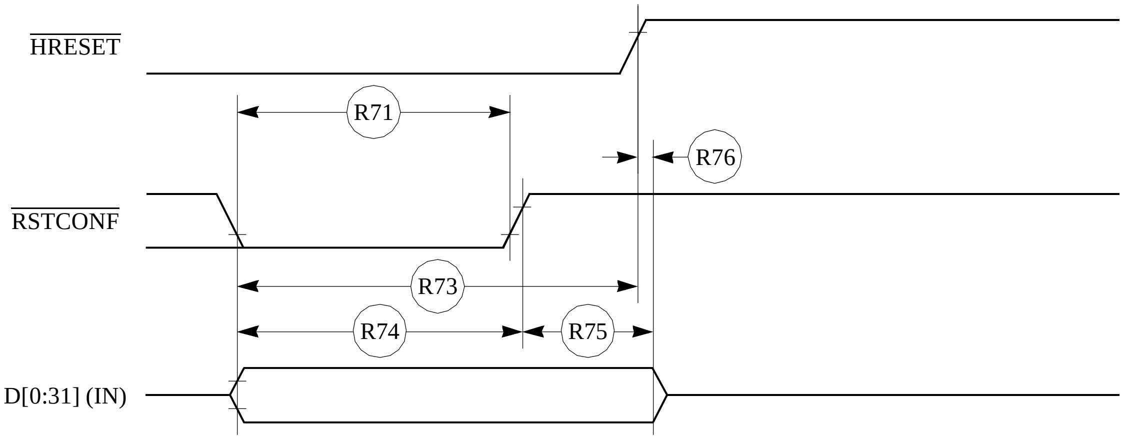


Figure 31. Reset Timing—Configuration from Data Bus

Figure 32 provides the reset timing for the data bus weak drive during configuration.

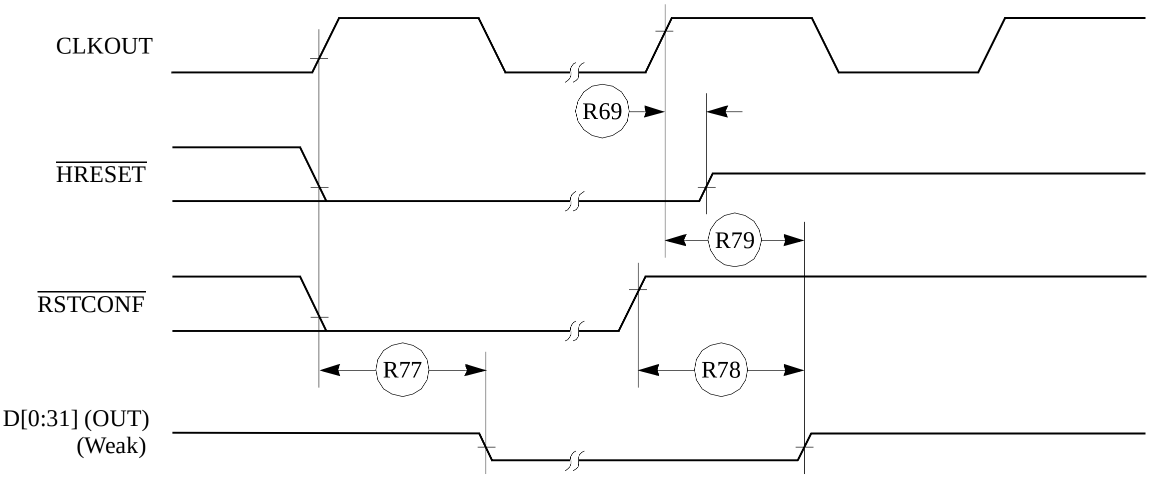


Figure 32. Reset Timing—Data Bus Weak Drive during Configuration

8.3 Baud Rate Generator AC Electrical Specifications

Table 15 provides the baud rate generator timings as shown in Figure 43.

Table 15. Baud Rate Generator Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
50	BRGO rise and fall time	—	10.00	ns
51	BRGO duty cycle	40.00	60.00	%
52	BRGO cycle	40.00	—	ns

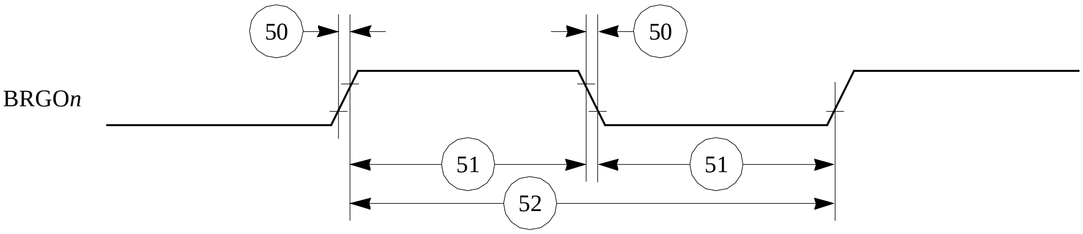


Figure 43. Baud Rate Generator Timing Diagram

8.4 Timer AC Electrical Specifications

Table 16 provides the baud rate generator timings as shown in Figure 44.

Table 16. Timer Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
61	TIN/$\overline{\text{TGATE}}$ rise and fall time	10.00	—	ns
62	TIN/$\overline{\text{TGATE}}$ low time	1.00	—	clk
63	TIN/$\overline{\text{TGATE}}$ high time	2.00	—	clk
64	TIN/$\overline{\text{TGATE}}$ cycle time	3.00	—	clk
65	CLKO high to $\overline{\text{TOUT}}$ valid	3.00	25.00	ns

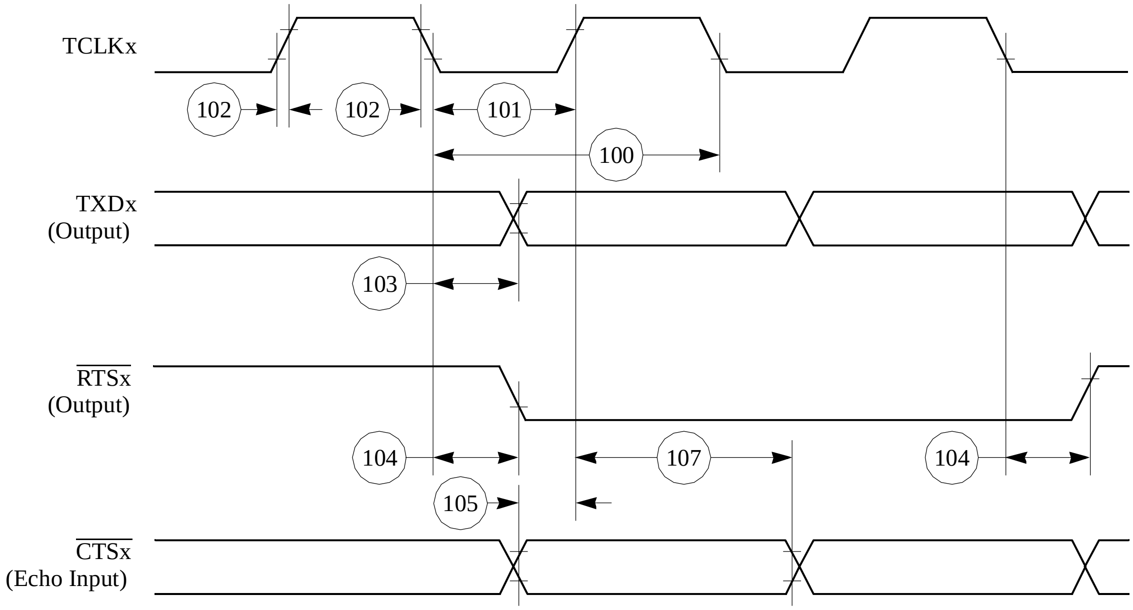


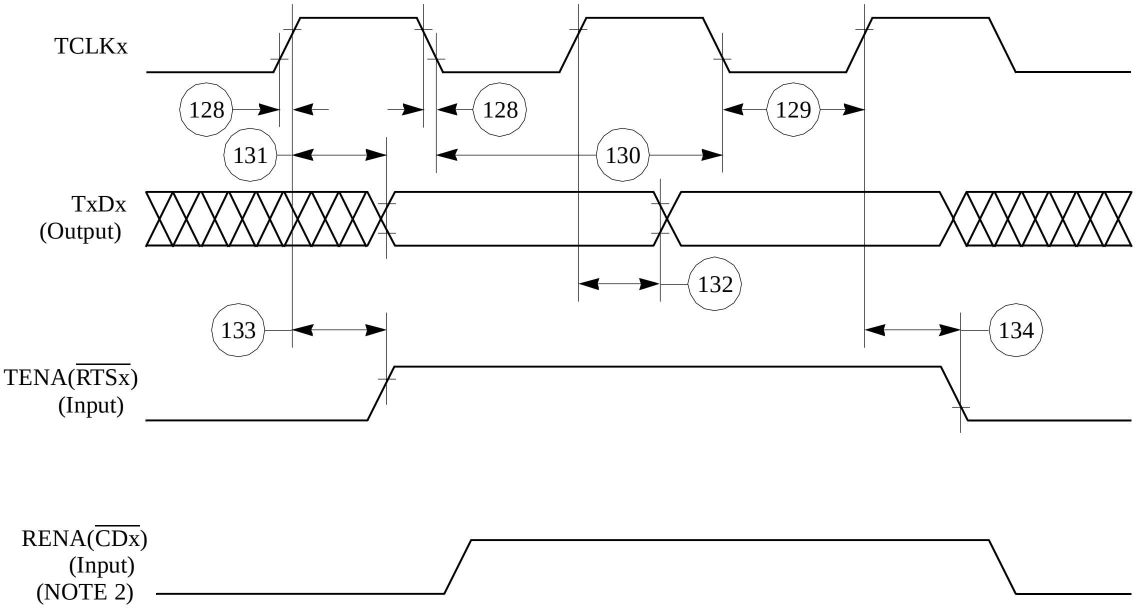
Figure 52. HDLC Bus Timing Diagram

8.7 Ethernet Electrical Specifications

Table 20 provides the Ethernet timings as shown in Figure 53 to Figure 55.

Table 20. Ethernet Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
120	CLSN width high	40.00	—	ns
121	RCLKx rise/fall time (x = 2, 3 for all specs in this table)	—	15.00	ns
122	RCLKx width low	40.00	—	ns
123	RCLKx clock period [1]	80.00	120.00	ns
124	RXDx setup time	20.00	—	ns
125	RXDx hold time	5.00	—	ns
126	RENA active delay (from RCLKx rising edge of the last data bit)	10.00	—	ns
127	RENA width low	100.00	—	ns
128	TCLKx rise/fall time	—	15.00	ns
129	TCLKx width low	40.00	—	ns
130	TCLKx clock period[1]	99.00	101.00	ns
131	TXDx active delay (from TCLKx rising edge)	10.00	50.00	ns
132	TXDx inactive delay (from TCLKx rising edge)	10.00	50.00	ns
133	TENA active delay (from TCLKx rising edge)	10.00	50.00	ns



NOTES:
1. Transmit clock invert (TCI) bit in GSMR is set.
2. If RENA is deasserted before TENA, or RENA is not asserted at all during transmit, then the CSL bit is set in the buffer descriptor at the end of the frame transmission.

Figure 55. Ethernet Transmit Timing Diagram

8.8 SMC Transparent AC Electrical Specifications

Figure 21 provides the SMC transparent timings as shown in Figure 56.

Table 21. Serial Management Controller Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
150	SMCLKx clock period [1]	100.00	—	ns
151	SMCLKx width low	50.00	—	ns
151a	SMCLKx width high	50.00	—	ns
152	SMCLKx rise/fall time	—	15.00	ns
153	SMTXDx active delay (from SMCLKx falling edge)	10.00	50.00	ns
154	SMRXDx/SMSYNx setup time	20.00	—	ns
155	SMRXDx/SMSYNx hold time	5.00	—	ns

[1] The ratio SyncCLK/SMCLKx must be greater or equal to 2/1.

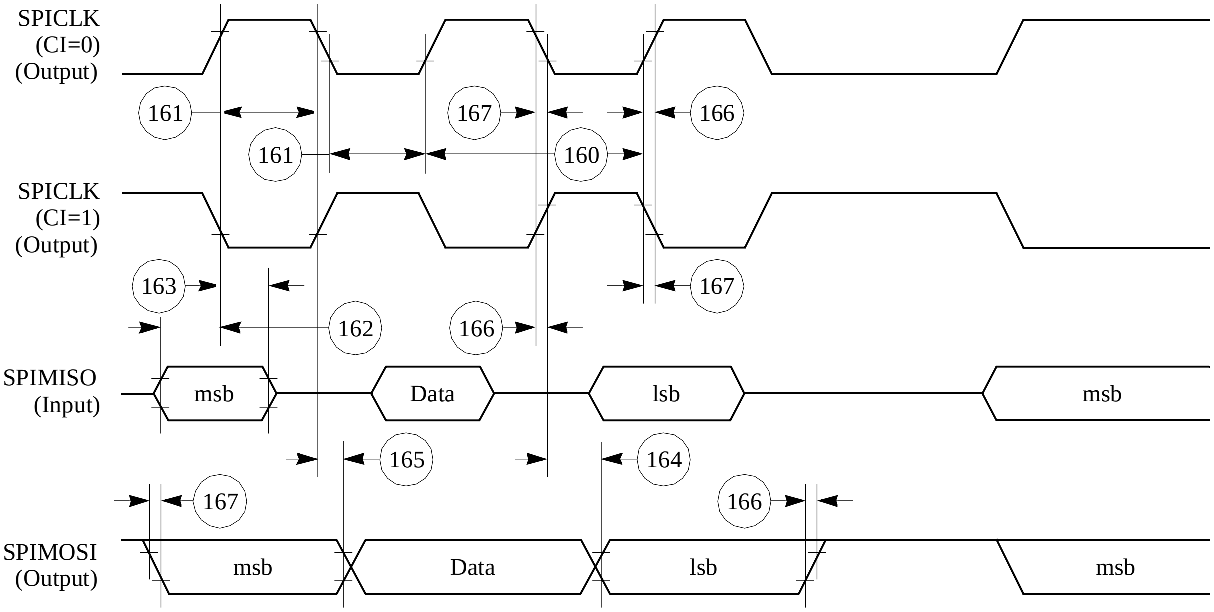


Figure 57. SPI Master (CP = 0) Timing Diagram

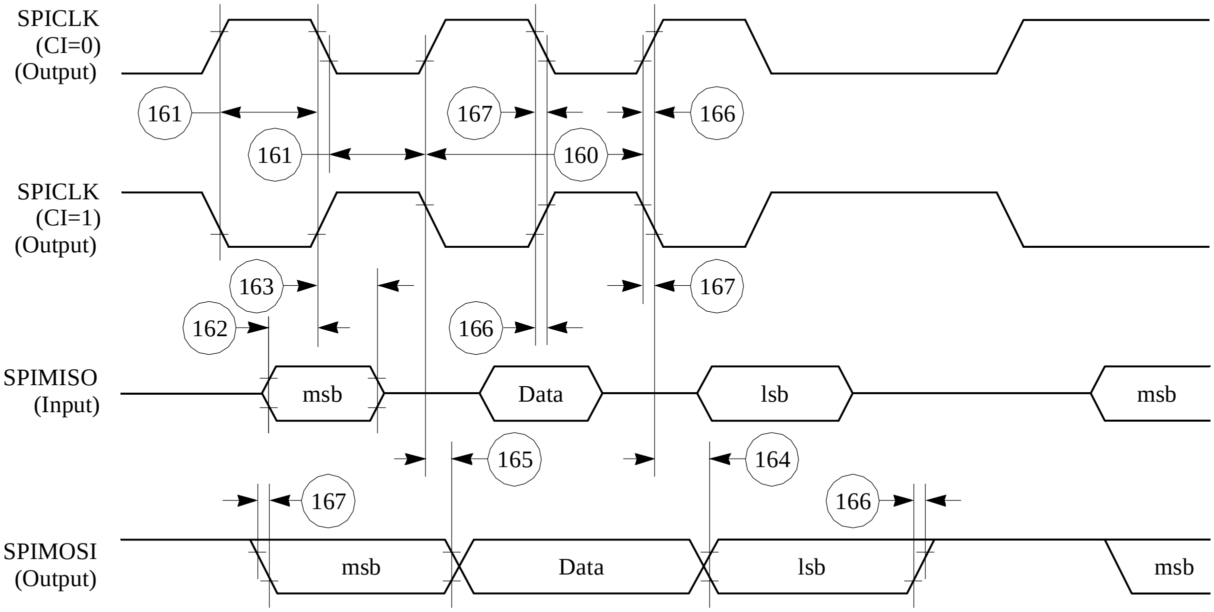
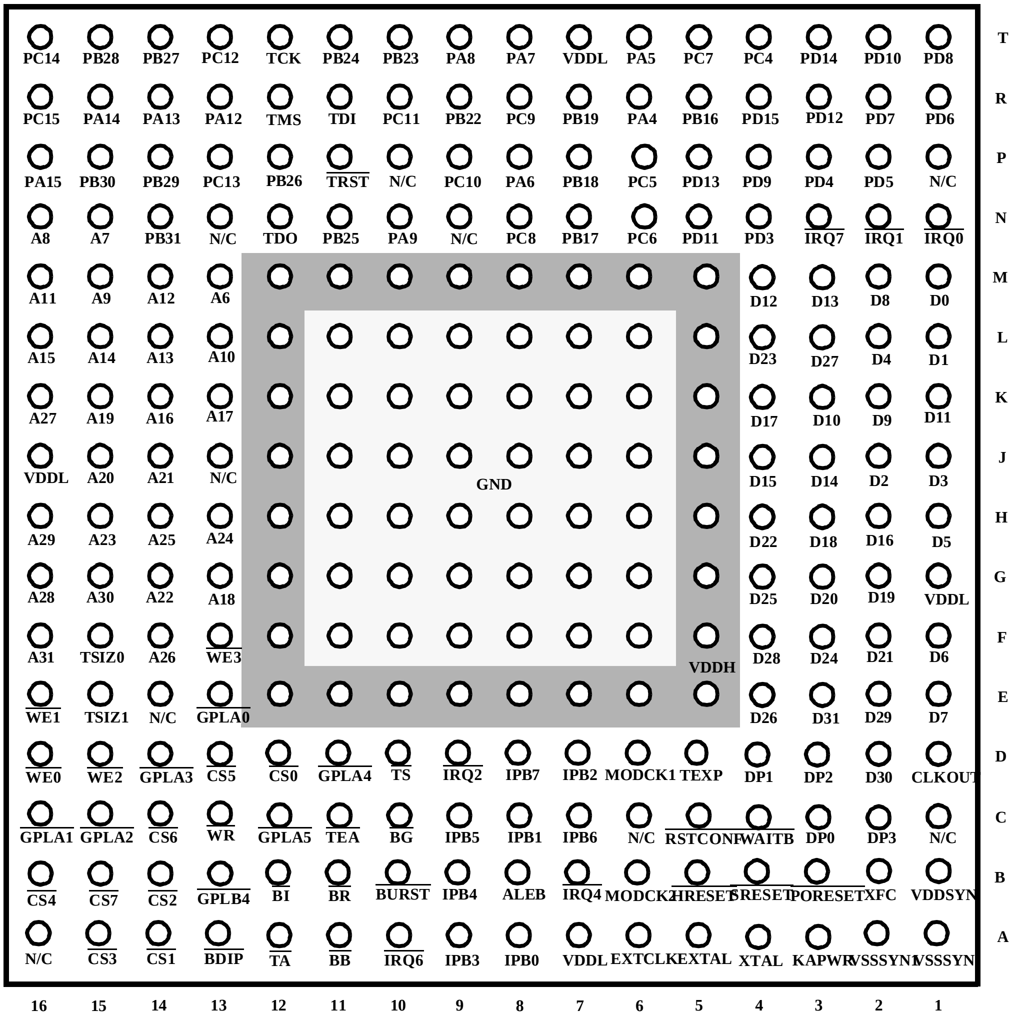


Figure 58. SPI Master (CP = 1) Timing Diagram

customers that are currently using the non-JEDEC pin numbering scheme, two sets of pinouts, JEDEC and non-JEDEC, are presented in this document.

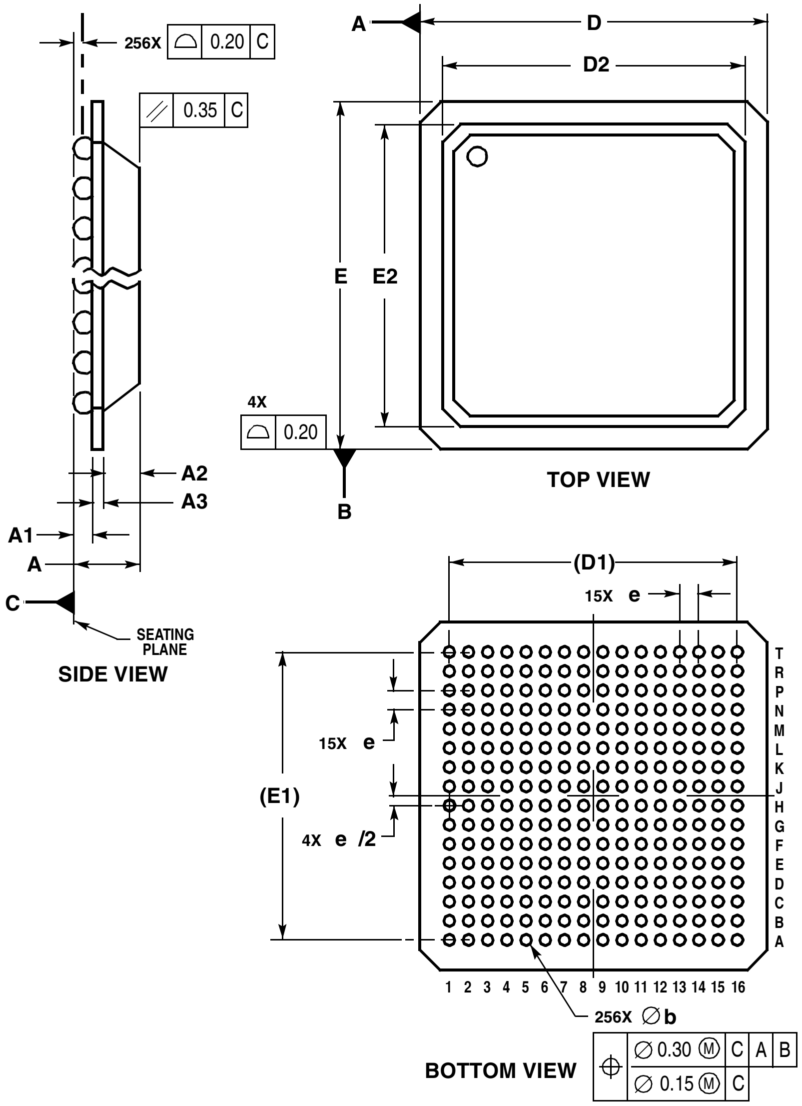
Figure 62 shows the non-JEDEC pinout of the PBGA package as viewed from the top surface.



	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1
T	PC14	PB28	PB27	PC12	TCK	PB24	PB23	PA8	PA7	VDDL	PA5	PC7	PC4	PD14	PD10	PD8
R	PC15	PA14	PA13	PA12	TMS	TDI	PC11	PB22	PC9	PB19	PA4	PB16	PD15	PD12	PD7	PD6
P	PA15	PB30	PB29	PC13	PB26	TRST	N/C	PC10	PA6	PB18	PC5	PD13	PD9	PD4	PD5	N/C
N	A8	A7	PB31	N/C	TDO	PB25	PA9	N/C	PC8	PB17	PC6	PD11	PD3	IRQ7	IRQ1	IRQ0
M	A11	A9	A12	A6									D12	D13	D8	D0
L	A15	A14	A13	A10									D23	D27	D4	D1
K	A27	A19	A16	A17									D17	D10	D9	D11
J	VDDL	A20	A21	N/C									D15	D14	D2	D3
H	A29	A23	A25	A24									D22	D18	D16	D5
G	A28	A30	A22	A18									D25	D20	D19	VDDL
F	A31	TSIZ0	A26	WE3									D28	D24	D21	D6
E	WE1	TSIZ1	N/C	GPLA0									D26	D31	D29	D7
D	WE0	WE2	GPLA3	CS5	CS0	GPLA4	TS	IRQ2	IPB7	IPB2	MODCK1	TEXP	DP1	DP2	D30	CLKOUT
C	GPLA1	GPLA2	CS6	WR	GPLA5	TEA	BG	IPB5	IPB1	IPB6	N/C	RSTCONF	WAITB	DP0	DP3	N/C
B	CS4	CS7	CS2	GPLB4	BI	BR	BURST	IPB4	ALEB	IRQ4	MODCK2	HRESET	SRESET	PORESET	XFC	VDDSYN
A	N/C	CS3	CS1	BDIP	TA	BB	IRQ6	IPB3	IPB0	VDDL	EXTCLK	EXTAL	XTAL	KAPWR	VSSSYN1	VSSSYN

Figure 62. Pin Assignments for the PBGA (Top View)—non-JEDEC Standard

Figure 64 shows the non-JEDEC package dimensions of the PBGA.



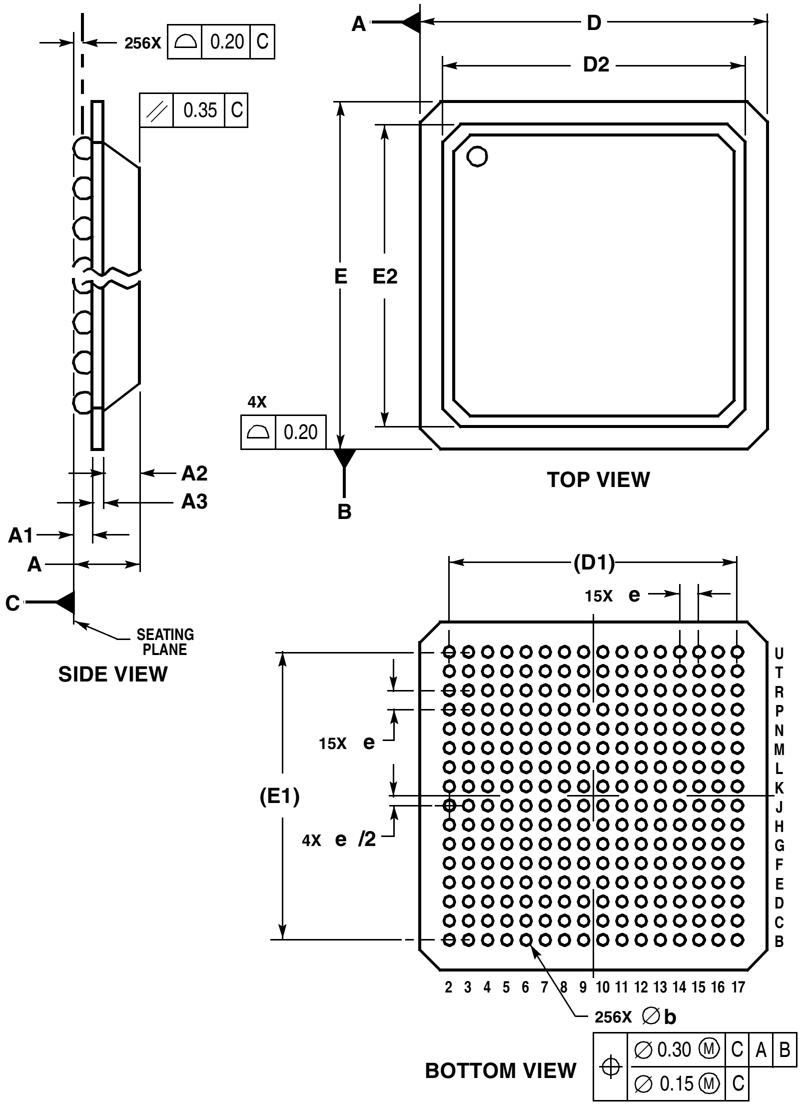
NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. DIMENSIONS IN MILLIMETERS.
3. DIMENSION b IS MEASURED AT THE MAXIMUM SOLDER BALL DIAMETER, PARALLEL TO PRIMARY DATUM C.
4. PRIMARY DATUM C AND THE SEATING PLANE ARE

	MILLIMETERS	
DIM	MIN	MAX
A	1.91	2.35
A1	0.50	0.70
A2	1.12	1.22
A3	0.29	0.43
b	0.60	0.90
D	23.00 BSC	
D1	19.05 REF	
D2	19.00	20.00
E	23.00 BSC	
E1	19.05 REF	
E2	19.00	20.00
e	1.27 BSC	

Figure 64. Package Dimensions for the Plastic Ball Grid Array (PBGA)—non-JEDEC Standard

Figure 65 shows the JEDEC package dimensions of the PBGA.



NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. DIMENSIONS IN MILLIMETERS.
3. DIMENSION b IS MEASURED AT THE MAXIMUM SOLDER BALL DIAMETER, PARALLEL TO PRIMARY DATUM C.
4. PRIMARY DATUM C AND THE SEATING PLANE ARE

	MILLIMETERS	
DIM	MIN	MAX
A	1.91	2.35
A1	0.50	0.70
A2	1.12	1.22
A3	0.29	0.43
b	0.60	0.90
D	23.00 BSC	
D1	19.05 REF	
D2	19.00	20.00
E	23.00 BSC	
E1	19.05 REF	
E2	19.00	20.00
e	1.27 BSC	

CASE 1130-01
ISSUE B

Figure 65. Package Dimensions for the Plastic Ball Grid Array (PBGA)—JEDEC Standard

THIS PAGE INTENTIONALLY LEFT BLANK

THIS PAGE INTENTIONALLY LEFT BLANK

THIS PAGE INTENTIONALLY LEFT BLANK

How to Reach Us:

Home Page:
www.freescale.com

email:
support@freescale.com

USA/Europe or Locations Not Listed:
Freescale Semiconductor
Technical Information Center, CH370
1300 N. Alma School Road
Chandler, Arizona 85224
(800) 521-6274
480-768-2130
support@freescale.com

Europe, Middle East, and Africa:
Freescale Halbleiter Deutschland GmbH
Technical Information Center
Schatzbogen 7
81829 Muenchen, Germany
+44 1296 380 456 (English)
+46 8 52200080 (English)
+49 89 92103 559 (German)
+33 1 69 35 48 48 (French)
support@freescale.com

Japan:
Freescale Semiconductor Japan Ltd.
Headquarters
ARCO Tower 15F
1-8-1, Shimo-Meguro, Meguro-ku
Tokyo 153-0064, Japan
0120 191014
+81 2666 8080
support.japan@freescale.com

Asia/Pacific:
Freescale Semiconductor Hong Kong Ltd.
Technical Information Center
2 Dai King Street
Tai Po Industrial Estate,
Tai Po, N.T., Hong Kong
+800 2666 8080
support.asia@freescale.com

For Literature Requests Only:
Freescale Semiconductor
Literature Distribution Center
P.O. Box 5405
Denver, Colorado 80217
(800) 441-2447
303-675-2140
Fax: 303-675-2150
LDCForFreescaleSemiconductor
@hibbertgroup.com

Information in this document is provided solely to enable system and software implementers to use Freescale Semiconductor products. There are no express or implied copyright licenses granted hereunder to design or fabricate any integrated circuits or integrated circuits based on the information in this document.

Freescale Semiconductor reserves the right to make changes without further notice to any products herein. Freescale Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does Freescale Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. “Typical” parameters which may be provided in Freescale Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including “Typicals” must be validated for each customer application by customer’s technical experts. Freescale Semiconductor does not convey any license under its patent rights nor the rights of others. Freescale Semiconductor products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the Freescale Semiconductor product could create a situation where personal injury or death may occur. Should Buyer purchase or use Freescale Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold Freescale Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that Freescale Semiconductor was negligent regarding the design or manufacture of the part.

Freescale™ and the Freescale logo are trademarks of Freescale Semiconductor, Inc.
All other product or service names are the property of their respective owners.

© Freescale Semiconductor, Inc., 2005.